

PATENT Customer No. 22,852 Attorney Docket No. 02887.0212

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Yuichiro YAMAZAKI, et al.

Application No.: 10/026,727

Filed: December 27, 2001

For: SUBSTRATE INSPECTION
SYSTEM AND METHOD FOR
CONTROLLING SAME

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

**AMENDMENT** 

In reply to the Office Action of February 18, 2003, with a period for response extending through June 18, 2003, by the attached Petition for Extension of Time and requisite fee payment, please amend the application as follows. Applicants also respectfully request the Examiner's reconsideration in view of the following remarks:

## IN THE DRAWINGS:

Filed herewith is a paper entitled "Submission of Corrected Formal Drawing," in which Examiner-required changes to Fig. 3 were made.

## IN THE ABSTRACT:

Please replace the current Abstract with the Substitute Abstract attached on a separate page. The full text of the Abstract in clean form is as follows:

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